fastmicro

| Sample Scanner

Upgrades & Options

Products

- 2-inch Wafer Interface
- SEM Stub / Particle Trap Holder
- Surface Particle Sampling Kit
- Surface Particle Sampler

Software

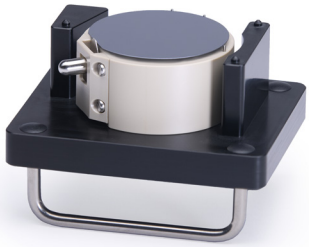
- Stand-alone Software License
- Advanced Workflow & Reporting

Training & Service

- SLA Preventive Maintenance & Calibration
- SLA On-Site Repair
- SLA SWOP & On-Site Repair
- Supervisor User Training

cleanliness control

| new
2-inch Wafer Interface



Fastmicro introduces the new 2-Inch Wafer Interface, designed to support Particle Deposition Rate Level (PDRL) measurements in a cost-effective and user-friendly manner. This interface enables the use of standard 2-inch wafers as particle traps or witness wafers, eliminating the need for costly consumables such as custom borosilicate glass substrates.
It features a dedicated 2-inch wafer holder that is fully backwards-compatible, allowing seamless integration with existing Sample Scanners already deployed in the field. Both the wafer and the puck are high-vacuum compatible, making them ideally suited for particle deposition monitoring in both cleanrooms and vacuum chambers.
With this addition, Fastmicro provides a practical and scalable solution for routine particle fallout monitoring, further expanding the applicability and value of the Fastmicro Sample Scanner platform.

| new
SEM stub / Particle Trap Holder

The Fastmicro SEM Stub / Particle Trap is a newly developed dual-function accessory designed for the Fastmicro Particle Contamination Samplers to streamline and accelerate particle contamination follow-up analysis workflows.
The SEM stub is developed to address the non-conductive nature of the sampling material, enabling analysis using SEM-EDX. This process is further sped up by providing the coordinates of the particles, enabled by markers in the sampler material and a pre-scan performed with the Fastmicro Sample Scanner.
Additionally, the stub functions as a holder for the Fastmicro Sampler to be used as a particle trap for measuring Particle Deposition Rate Levels (PDRL).
This innovation enhances both analytical follow-up measurements and PDRL measurements within a single setup.

| new
Surface Particle Sampling Kit

The Fastmicro Surface Particle Samplng Kit introduces a new, optimized sampling method that improves both cost-efficient and consistent surface particle sampling. The kit includes a sampling tool designed for fixed-force application to ensure repeatability and prevent cross-contamination, along with a sample holder that is backward-compatible with existing Fastmicro Sample Scanners.
This innovation enables efficient removal of submicron particles and supports cost-effective, repeatable particle measurement with the Fastmicro Sample Scanner.

- Sampler Operator Tool
- Sampler Holder
- Base plate for Sample Scanner Interface
- 6 SP Samplers

| new

Surface Particle Sampler

Fastmicro's Surface Particle (SP) Sampler is a high-performance submicron surface particle removal medium for indirect measurement of surface contamination levels, enabling repeatable quantification of particle count, size, and location.

The ultra- clean 'tape-lift' SP Sampler allows flexible sampling on a wide variety of surfaces, including hard-to-reach or curved surfaces, without leaving any significant measurable residue. Used in combination with the Fastmicro Sampler Operator Tool, the SP Sampler ensures consistent, operator-independent and high-efficiency particle pickup from various surface types and materials. The SP Sampler can be measured within seconds using the Fastmicro Sample Scanner, allowing fast inspection of particles down to 0.5 µm.

| software

Stand-alone Software License

Fastmicro's standalone software enables you to perform measurement post-processing and advanced analysis directly on your own PC, without the need to enter the cleanroom. Work efficiently outside the cleanroom with full access to powerful data insights.

| software

Advanced Workflow & Reporting

Users can generate a qualification report based on a single measurement or a comparison between pre and post measurements (adder analysis). We also offer a database interface via an XML-file. This will help Sample Scanner users to qualify parts more easily and enable them to easliy communicate their Fastmicro results with suppliers and/or customers.

Advanced reporting gives the ability to configure the output criteria to either customer requirements or own inhouse specifications. A custom logo can be added as well.
The output is generated in the following file formats: PDF qualification report, XML report and KLARF file.

| service
Service Level Agreements

Fastmicro is a technology leader in advanced surface particle contamination inspection equipment and scanners. We are dedicated to providing world-class service to our customers in the global microtechnology industries.

From our headquarters and global return & repair service center in Geldrop, the Netherlands, we support our customers with our Service Level Agreements for reliable particle measurement and analyses. A second return & repair service center is located in Bethel (CT), US.

Preventive Maintenance & Calibration
Secure synchronized performance with calibration and maintenance inspections.

On-Site Repair

Secure uptime with a service engineer on standby.

Swop & On-Site Repair

Secure your business-critical environments uptime with a replacement scanner.

| training
Supervisor User Training

This 4-hour training is intended for supervisor users and aims to instruct them in the operation of the Fastmicro Sample Scanner and to teach others how to operate it.

Note: one training for maximum 4 persons is standard included with the purchase of a Fastmicro Sample Scanner.

About Us - At Fastmicro we help our customers to overcome today's cleanliness challenges in microtechnology. We believe you can accomplish breakthroughs in cleanliness control with fast, accurate and quantitative surface particle measurements. We enable process quality engineers to make reliable decisions on where and how to improve their cleanliness processes and deliver consistent quality products, ultimately achieving high equipment performance for their end users.

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